

CFN Instruments available for NSLS-II General User proposals

Category	Instrument
Electron Microscopy	High Resolution Analytical Scanning Electron Microscope
Electron Microscopy	Scanning Electron Microscope (SEM)
Scanning and Probing Microscopy	Ambient Scanning Probe Microscope
Scanning and Probing Microscopy	Environmental Atomic Force Microscope, Video-Rate Capability
Scanning and Probing Microscopy	Environmental Closed Loop Atomic Force Microscope
Electrical Probing	Battery Tester
Electrical Probing	Room Temperature Electrical Probe Station
X-Ray and Light Scattering	Miniflex X-Ray Diffractometer
Solution Based & Biomolecular Methods	Particle Sizing and Tracking
Thermal Analysis, Annealing and Electrochemistry	Differential Scanning Calorimeter (DSC)
Thin Film Metrology	Dektak 150 Stylus Profilometer
Deposition	Spin Coater